Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/681,815	KEVER ET AL.	
Examiner	**Art Unit**	
Sun J. Lin	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	2	1/19/2006	JSL
716	11	1/19/2006	JSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	**2**	**1/19/2006**	**JSL**
716	11	1/19/2006	JSL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	1/19/2006	JSL
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	1/20/2006	JSL
IEEE	1/20/2006	JSL